# Bayesian electron spectrum reconstruction from dose-depth profiles 

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## Bayesian

Function: adjective
being, relating to, or involving statistical methods that assign probabilities or distributions to events (as rain tomorrow) or parameters (as a population mean) based on experience or best guesses before experimentation and data collection, and that apply Bayes' theorem to revise the probabilities and distributions after obtaining experimental data.

## The Physical Problem


a) space-charge repulsion
b) stray magnetic fields

$$
\begin{aligned}
& D(x)=\int_{0}^{\varepsilon_{\max }} d \varepsilon W(x, \varepsilon) S(\varepsilon) \\
& S(\varepsilon)=?
\end{aligned}
$$



Dose-depth profile ( 6 MeV electrons in water)

Fredholm integral equation ( $1^{\text {st }}$ kind): an ill-posed mathematical problem!

Additional complications due to beam's size and emittance/divergence exist as well.

## The Status Quo

i) Bayesian methods in similar problems:

Rutherford Back-Scattering ( H or He ions $\sim 1 \mathrm{MeV}$ ):
(e.g. R. Fisher et al., Phys. Rev. E55 p. 6667 (1997))



Apparatus Function Determination (mono-isotopic Co has a single narrow line)


Spectrum Deconvolution
(Cu layer on Si substrate)

## The Status Quo

ii) Ad hoc methods in electron spectrum reconstruction problems
e.g. A. Chvetsov et al. Med. Phys. 29 p. 578 (2002)


No regularization, brute force
a) 6 MeV


Tichonov regularization and spectrum splitting into smooth and peaked parts


$$
\begin{aligned}
& \int_{0}^{\varepsilon_{\max }} d \varepsilon W(x, \varepsilon) F(\varepsilon)=0 \\
& S(\varepsilon) \rightarrow S(\varepsilon)+F(\varepsilon)
\end{aligned}
$$

An example of inference: $\quad$ a) If $A$ is true, than $B$ is true as well (prior information);
b) $A$ is false (data from experiment);
c) B is less plausible (than before the experiment)

## Basic Probability Theory I

Notations:
$P(A) \quad:$ Probability of $A$ being true
$P(\bar{A}) \quad:$ Probability of $A$ being false (.not.A being true)
$P(A \mid B) \quad$ : Probability of $A$ being true provided that $B$ is true
$P(A \mid B C)$ : Probability of $A$ being true provided that both $B$ and $C$ are true

## Basic Probability Theory II

"common sense reduced to calculation" (Laplace)

Range:

$$
P(A) \in[0,1]
$$

Sum rule:

$$
P(A)+P(\bar{A})=1
$$

Product rule: $\quad P(A B \mid C)=P(A \mid B C) P(B \mid C)$

Bayes' theorem (in its simplest form) is an immediate consequence of the above product rule and the commutativity of propositions:

$$
P(A B)=P(B A)
$$

## Bayes' Theorem

H - hypothesis
D - data
I - prior information

$$
P(H D \mid I)=P(H \mid D I) P(D \mid I)=P(D \mid H I) P(H \mid I)=P(D H \mid I)
$$

sampling distribution / likelihood


## Bayes' Theorem as a Learning Prescription



In 1946, R.T. Cox proved that any consistent scheme of logical inference must be equivalent to probability theory as described

## Least-Informative Priors

a) Discrete probabilities: Principle of Insufficient Reason
b) Continuous probabilities: Symmetries / Invariance requirements

$$
\begin{array}{ll}
\text { Example: } & N(t)=N_{0} \exp (-\lambda t) \quad P(\lambda) d \lambda \sim d \lambda \\
& N(t)=N_{0} \exp (-t / \tau) \quad P(\tau) d \tau \sim d \tau \sim d \lambda / \lambda^{2} \\
P(\lambda) d \lambda \stackrel{ }{=} P\left(a \lambda^{\prime}\right) d\left(a \lambda^{\prime}\right) \Rightarrow P(\lambda) d \lambda \sim \frac{d \lambda}{\lambda} \sim \frac{d \tau}{\tau} \quad \text { (Jeffrey's prior) }
\end{array}
$$

MAXENT principle (Jaynes'1957, but originally Gibbs'1902):

$$
S=-\int d x P(x) \ln \frac{P(x)}{P_{0}(x)} \rightarrow \max
$$

(Kullback-Leibler ('51) relative entropy)

## The uniqueness of entropy

One seeks a "ranking" scheme $R(p)$ for probability distributions $p(y)$ :
i) Locality: $\quad R(p)=\int d y f(p(y))$
ii) Invariance: $\quad R(p)=\int d y \mathrm{p}(y) f\left(\frac{p(y)}{m(y)}\right)$
iii) Consistency for independent systems:

$$
\begin{aligned}
& R\left(p_{1} p_{2}\right)=R\left(p_{1}\right)+R\left(p_{2}\right) \\
& \int d y_{1} \mathrm{dy}_{2} \mathrm{p}_{1}\left(y_{1}\right) \mathrm{p}_{2}\left(y_{2}\right) f\left(\frac{\mathrm{p}_{1}\left(y_{1}\right) \mathrm{p}_{2}\left(y_{2}\right)}{m_{1}\left(y_{1}\right) m_{2}\left(y_{2}\right)}\right)=\int d y_{1} \mathrm{p}_{1}\left(y_{1}\right) f\left(\frac{\mathrm{p}_{1}\left(y_{1}\right)}{m_{1}\left(y_{1}\right)}\right)+\int \mathrm{dy}_{2} \mathrm{p}_{2}\left(y_{2}\right) f\left(\frac{\mathrm{p}_{2}\left(y_{2}\right)}{m_{2}\left(y_{2}\right)}\right) \\
& \quad \text { for } \int d y p(y)=1 \quad \Rightarrow f(p)=\ln (p)
\end{aligned}
$$

thus

$$
R(p)=\int d y \mathrm{p}(y) \ln \left(\frac{p(y)}{m(y)}\right)
$$

## The Likelihood

Gaussian likelihood function (just one of many possible):

$$
\begin{gathered}
P(D \mid H I)=\frac{\exp \left(-\frac{\chi^{2}}{2}\right)}{\prod_{i=1}^{N} \sqrt{2 \pi} \sigma_{i}} \\
\chi^{2}=\sum_{i=1}^{N}\left(\frac{D_{i}-F_{i}(H)}{\sigma_{i}}\right)^{2}
\end{gathered}
$$

Here, $\sigma_{i}$ is the error of the measurement of the $i$-th data point $D_{i}$ and $F_{i}(S)$ is the calculated value of $D_{i}$ assuming $H$.

## Application to the problem at hand

i) Discretization:

$$
\begin{aligned}
& D(x)=\int_{0}^{\varepsilon_{\max }} d \varepsilon W(x, \varepsilon) S(\varepsilon) \\
& S(\varepsilon)=?
\end{aligned}
$$

Fredholm equation

$$
\begin{aligned}
& d_{i}=\sum_{j} W_{i j} s_{j} \\
& s_{i}=\text { ? }
\end{aligned}
$$

$$
\begin{aligned}
& S(\varepsilon)=\sum_{i=1}^{N} s_{i} F_{i}(\varepsilon) \\
& \int d \varepsilon F_{i}(\varepsilon) F_{j}(\varepsilon)=\delta_{i j} \\
& \sum_{i=1}^{\infty} F_{i}(\varepsilon) F_{i}\left(\varepsilon^{\prime}\right)=\delta\left(\varepsilon-\varepsilon^{\prime}\right)
\end{aligned}
$$

Too fine a mesh (too big a basis) carries the danger of overfitting (ringing).

$$
\begin{aligned}
& d_{i}=\int d x D(x) G_{i}(x) \\
& W_{i j}=\iint d x d \varepsilon W(x, \varepsilon) G_{i}(x) F_{j}(\varepsilon) \\
& s_{i}=\int d \varepsilon S(\varepsilon) F_{i}(\varepsilon)
\end{aligned}
$$

## Application to the problem at hand

ii) The "hypothesis":

Every set of $s_{i}$ gives us a spectrum $\quad S(\varepsilon)=\sum_{i=1}^{N} \sqrt{s_{i}} F_{i}(\varepsilon)$

$$
\begin{aligned}
& H: s_{1} \in\left\{s^{(1)}, d s\right\} \cap s_{2} \in\left\{s^{(2)}, d s\right\} \cap \cdots s_{N} \in\left\{s^{(N)}, d s\right\} \\
& P(H \mid X)=P\left(s_{1} \in\left\{s^{(1)}, d s\right\} \cap s_{2} \in\left\{s^{(2)}, d s\right\} \cap \cdots s_{N} \in\left\{s^{(N)}, d s\right\} \mid X\right)
\end{aligned}
$$

iii) The "prior":

The choice of the prior is where the art in this science is!
For the sake of example, the joint Jeffrey's prior would be

$$
P(H \mid I) \sim\left[\prod_{i=1}^{N}\left|s^{(i)}\right|\right]^{-1}
$$

## Application to the problem at hand

ii) The Bayes theorem and the inferred spectrum:

$$
P(\{s\} \mid D I) \sim \frac{\exp \left(-\frac{1}{2} \sum_{i=1}^{N}\left(\frac{d_{i}-D_{i}(s)}{\sigma_{i}}\right)^{2}\right)}{\prod_{k=1}^{M} \sigma_{k} \prod_{i=1}^{N}\left|s^{(i)}\right|}
$$

The most probable spectrum:

$$
\left.P(\{s\} \mid D I) \rightarrow \max \right|_{\{s\}}
$$

The inferred spectrum:

$$
\bar{s}_{i}=\int d^{N} S S_{i} \frac{\exp \left(-\frac{1}{2} \sum_{i=1}^{N}\left(\frac{d_{i}-D_{i}(s)}{\sigma_{i}}\right)^{2}\right)}{\prod_{k=1}^{M} \sigma_{k} \prod_{i=1}^{N}\left|s^{(i)}\right|}
$$

The multiple integral is best taken by Monte Carlo methods. If the results are to be trusted, the most probable and the average spectra should be fairly similar.

## Application to the problem at hand

iv) The Bayesian approach produces estimates of the quality of the result as well!
$\left(\Delta \bar{s}_{i}\right)^{2}=\int d^{N} s\left(s_{i}-\bar{s}_{i}\right)^{2} \frac{\exp \left(-\frac{1}{2} \sum_{i=1}^{N}\left(\frac{d_{i}-D_{i}(s)}{\sigma_{i}}\right)^{2}\right)}{\prod_{k=1}^{M} \sigma_{k} \prod_{i=1}^{N}\left|s^{(i)}\right|}$

It can be shown that whenever

$$
\frac{\left|\Delta \bar{s}_{i}\right|}{\left|s_{i}\right|} \ll 1
$$

the most-probable and the average spectra are "close".


## Experimental



The initial part of the profile (for small depths) is overly sensitive to electron beam divergence and therefore should be discarded.

## Theoretical



## Work to be done

i) modification of the MCNPX code to track electrons in external magnetic and electric fields;
ii) calculation of dose-depth profile database(s) for a range of electron energies and beam divergences;
ii) Bayesian deconvolution algorithm development and software implementation;
iv) code(s) validation and testing.

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